INFORMATION DISCLOSURE (

ION (Use several sheets if necessary)

ATTY DOCKET NO. 02008.071001; AD-024	SER	JALNO.	9	8	0	8
R		CT/PTO				

02008.071001; AD-02	TUS SI		980)89	31
Masahiro ISHIDA et	are Rec'd	PCT/PTC	03	DEC	200
FILING	G	ROUP			

U.S. PATENT DOCUMENTS FILING DATE *EXAMINER SUBCLASS NAME CLASS DOCUMENT NUMBER DATE IF APPROPRIATE INITIAL **FOREIGN PATENT DOCUMENTS** TRANSLATION SUBCLASS COUNTRY CLASS DATE DOCUMENT NUMBER YES NO J A1 02/23/1993 H05-45423 Japan Ta A2 H10-4128 01/06/1998 Japan **A3** 03/26/1993 Japan TO H05-74911 08/28/1985 B A4 60-165562 Japan TV **A5** 10-253710 09/25/1998 Japan OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) B. Kruseman et al., "Transient Current Testing of 0.25 m CMOS Devices", ITC Int'l. Test Conf., September 28-30, 1999, Tar pages 47-56 **A6 DATE CONSIDERED** EXAMINER 4/26/03 *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not

Form PTO-A820 (also form PTO-1449)

considered. Include copy of this form with next communication to applicant.

P09C/REV03

SERIAL NO. ATTY DOCKET NO.

INFORMATION DISCLOSURE (ION					Masahiro ISHIDA et al. JC13 Rec'd PCT/PTO 0 3 DEC 20						
			Use several sheets if necess		1						
						FILING	G	ROUP			
				U.:	S. PATENT	DOCUMENTS	····				
EXAMINER		DOCUMENT NUMBER DATE			NAME		CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
		1		†	<u> </u>						
<u> </u>		+			 						
	<u> </u>	+							 		
	-	+			-						
	-	+		 							
		\dagger		 					 	i	
	\vdash	+									
		+		 							
		+		 	 						
· · · · · · · · · · · · · · · · · ·		+-		 	 						
	L			FORE	IGN PATE	NT DOCUMENTS			L		
			DOCUMENT NUMBER	DATE		COUNTRY	CLASS	SUBCLASS	TRANSL		
pa	B 1	9-8	80114	03/28/1997	Japan				YES	NO V	
jr	B2	9-5	54140	02/25/1997	Japan					1	
JW.	В3	11-	94917	04/09/1999	Japan					1	
W	B4	10-	239394	09/11/1998	Japan	<u></u>				1	
<i>T</i> √	B5	9-2	92444	11/11/1997	Japan					1	
			OTHER DOCUME	NTS (Includin	l ng Author	, Title, Date, Pertine	ent Pages, Etc.)		<u> </u>		
								C 6 1007			
X		B6	J. S. Beasley et al., "iDD 32-29	Pulse Response	Testing Ap	pplied to Complex CM	OS ICs, Int'l. Tes	t Conf. 1997,	Vol. 1997, _l	pages	
XAMINE	₹ /	M				DATE CONSIDERED	4/20/03				
4/ = / 63											

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



ATTY DOCKET NO. 02008.071001; AD-024

_{rus} | se**tr9**7 980891

Masahiro ISHIDA et al. 48 Res LEGIPTO 0 3 DEC 2011

FILING GROUP

U.S. PATENT DOCUMENTS												
*EXAMINER		DO	OCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	FILING DATI			
							1					
							1					
	 						1	 				
		ļ				- 1 3 7 7 7			 			
	 						 					
							 					
	_						+					
					 		†					
	<u> </u>			FORE	IGN PATE	ENT DOCUMENTS		<u> </u>	1			
		DO	CUMENT NUMBER	DATE		COUNTRY	CLASS	SUBCLASS		TRANSLATION YES NO		
P	C1	2001-91	1568	04/06/2001 Japa					152	NO ✓		
-	 						1	<u></u>				
	 						 					
	 						+					
	 	 			<u> </u>		 					
<u>_</u>	L	L	OTHER DOCUMEN	NTS (Includin	a Authoi	r, Title, Date, Pertinent	Pages, Etc.)		<u></u>			
(motioning riamon, riad, pate), rotational agos, pate)												
EXAMINER M					DATE CONSIDERED							
	EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.											